

Bayes Rule :

$$P(E_1|E_2) = \frac{P(E_2|E_1)P(E_1)}{P(E_2|E_1)P(E_1) + P(E_2|E_1')P(E_1')}, \text{ where } E_1 \text{ and } E_1' \text{ are mutually exclusive and collectively exhaustive}$$

Example :

Let us consider ^{at} lossy wireless channel. The probability of loss is as follows: prob of loss while transmitting 0 is 0.05 and while transmitting 1 is 0.1. Besides, probability of transmitting 1 is 0.6 and transmitting 0 is 0.4. Now, we have received an 1. What is the probability that the actual sent bit was 0.

Soln :

$E_1 \rightarrow$ Event of transmitting a 0 $\Rightarrow P(E_1) = 0.4$

$E_1' \rightarrow$ " " " " an 1 $\Rightarrow P(E_1') = 0.6$

$E_2 \rightarrow$ " " " receiving an 1 $\Rightarrow P(E_2) \rightarrow$ Not known

$P(E_2|E_1) = 0.05$; $P(E_2|E_1') = 1 - P(E_2|E_1) = 1 - 0.1 = 0.9$

$$\begin{aligned} \text{Now, } P(E_1|E_2) &= \frac{P(E_2|E_1)P(E_1)}{P(E_2|E_1)P(E_1) + P(E_2|E_1')P(E_1')} \\ &= \frac{0.05 * 0.4}{0.05 * 0.4 + 0.9 * 0.6} = \frac{1}{28} \end{aligned}$$

Bernoulli trials : N independent repetitions of a random experiment, which has two possible outcomes

- Let $P(\text{success}) = p$, $P(\text{failure}) = q$

Then, $P(k \text{ successes in } n \text{ trials}) = \binom{n}{k} p^k q^{n-k} = \binom{n}{k} p^k (1-p)^{n-k}$

- Example problem : TMR reliability comput? \rightarrow (Exercise, do yourself!)

* Discrete random variable : Takes values from a set of discrete numbers \leftarrow 2 different types of defn

* Contd : " " " Assigns a real number to an uncountable event space's events

* Probability Mass Function (pmf) : Gives probability that the value of a discrete random variable X is equal to x . It is denoted by $f_X(x)$.

$$f_X(x) = P(X=x)$$

$$\sum_{x \in A} f_X(x) = 1$$

* Cumulative Distribution Function (cdf) : Gives probability that the value of a random variable remains within a certain value. It is denoted by $F_X(x)$.

$$F_X(x) = P(X \leq x)$$

$$P(a < X \leq b) = F_X(b) - F_X(a) \text{ [Prob of remaining within a range]}$$

$$\lim_{x \rightarrow -\infty} F_X(x) = 0 ; \lim_{x \rightarrow +\infty} F_X(x) = 1 ;$$

$$F_X(x) = \sum_{t \in A, t \leq x} f_X(t) \text{ [for discrete var]}$$

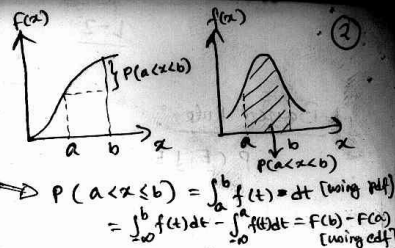
$$F_X(x) = \int_{-\infty}^x f(t) dt \text{ [for contd var]}$$

\leftarrow pmf

* Probability ^{Denoting} Mass Function (pdf) : Gives relative likelihood of a random contd variable of taking a given value.

$$f_x(x) = \frac{P(X \leq x+dx) - P(X \leq x)}{dx}$$

$$= \frac{F(x+dx) - F(x)}{dx} = \frac{dF(x)}{dx}$$



Some simple random variables

Discrete:

(1) Binomial: the # of successes in n independent trials (Bernoulli trial)

$$\text{pmf} \rightarrow \binom{n}{k} p^k (1-p)^{n-k} = P(k) \quad [\text{cdf} \rightarrow \text{not needed}]$$

Example:

Vendor 1 \rightarrow produces 1000 units where $P(\text{defective}) = .01$

Vendor 2 \rightarrow produces 2000 units where $P(\text{defective}) = .01$

Let both ship 100 units each. Which shipment has the higher probability of having 5 defectives?

$$v1 \rightarrow \binom{100}{5} (.01)^5 (.99)^{95}$$

$$v2 \rightarrow \binom{100}{5} (.01)^5 (.99)^{95} \quad \left\{ \text{Same!} \right.$$

(2) Geometric: the # of trials till the first success in Bernoulli trials

$$\text{pmf} \rightarrow P(X=k) = (1-p)^{k-1} p = P(k)$$

\uparrow
 $P(k^{\text{th}} \text{ trial is the first success})$

$$\left\{ \begin{array}{l} \text{cdf} \rightarrow 1 - (1-p)^{k+1} \end{array} \right.$$

Example:

What is the prob of picking 10th element in a shipment as its first defective?

$$P(X=10) = (1-0.01)^{10-1} \cdot (0.01)^1$$

$$\text{Poisson} \quad \sum_{k=1}^{\infty} P(k) = \sum_{k=1}^{\infty} p(1-p)^{k-1} = p \sum_{k=1}^{\infty} (1-p)^{k-1} = p \sum_{k=0}^{\infty} (1-p)^k = p \cdot \frac{1}{1-(1-p)} = p \cdot \frac{1}{p} = 1$$

$$E(\# \text{ of trials till success}) = \sum_{k=1}^{\infty} k P(k) = \sum_{k=1}^{\infty} k p (1-p)^{k-1}$$

$$= \sum_{k=1}^{\infty} k (1-p)^{k-1} p = \sum_{k=1}^{\infty} (k-1+1) (1-p)^{k-1} p = \sum_{k=1}^{\infty} (k-1) (1-p)^{k-1} p + \sum_{k=1}^{\infty} (1) (1-p)^{k-1} p$$

$$= \sum_{k=1}^{\infty} (k-1) (1-p)^{k-1} p + \sum_{k=1}^{\infty} (1-p)^{k-1} p = \sum_{k=1}^{\infty} k (1-p)^{k-1} p - \sum_{k=1}^{\infty} (1-p)^{k-1} p + \sum_{k=1}^{\infty} (1-p)^{k-1} p = \sum_{k=1}^{\infty} k (1-p)^{k-1} p = \frac{1}{1-p} = \frac{1}{p}$$

(3) Poisson: Gives the prob of k (or failures) arrivals (or events) in interval $(0, t]$

- Rate of arrival (constant) is λ . Here, a single parameter is $\alpha = \lambda t$.

$$\text{pmf} \rightarrow \frac{(\lambda t)^k}{k!} e^{-\lambda t} \quad \left\{ \begin{array}{l} [k \text{ is the \# of events}] \\ \rightarrow k \text{ failures in time } t \end{array} \right.$$

$$R(t) = P(k=0 \text{ at time } t) = e^{-\lambda t}$$

Example: probability of k components failing in time λt

④ Hypergeometric: Prob of k successes in n trials [success \leftrightarrow defective]
- Gives probability of k defectives while n samples are drawn from a total of m items having d defectives
($m-d$)

$\text{Prob of } k \text{ successes from } n \text{ trials}$

$\text{with replacement} \Rightarrow \text{Binomial}$

$\text{without} \Rightarrow \text{Hypergeometric}$

has comes from independent trials

① Exponential: ~~dis~~ Gives inter-arrival time where arrival follows a poisson process.

$$X \sim \text{Exp}(\lambda)$$

$$F(x) = 1 - e^{-\lambda x}, \quad x \geq 0$$

$$P(Y \leq y | X > t) = P(X \leq y), \text{ independent of } t$$

here, $Y = X - t$
 so, $P(X \leq y + t | X > t) = P(X \leq y)$ [as $Y \leq y \Rightarrow X - t \leq y \Rightarrow X \leq y + t$]
 to time t . what is the

Derivati:

rel. bet.
exp and
Poisson

Here, $P(\text{component will fail in time } t) = F(t)$ following exp
 $= 1 - P(\text{No failure in time } t) = 1 - P(N_t = 0 \text{ in poisson process})$
 $= 1 - e^{-\lambda t} \cdot \frac{(\lambda t)^0}{0!} = 1 - e^{-\lambda t} \rightarrow \text{Exponential distr.}$

Reliability: $R(t) = 1 - \text{Prob}(\text{Component fails in time } t)$

$$= 1 - F(t)$$

$$R'(t) = -f(t); \text{ as } f(t) = F'(t)$$

Now,

$P(\text{Component will not survive an additional time } x | \text{ survived till time } t)$

$$= \frac{P(t < X < t+x)}{P(X > t)} = \frac{F(t+x) - F(t)}{R(t)} \quad [\text{Similar to prev. deriv.}]$$

Now, instantaneous failure rate will be

$$h(t) = \lim_{x \rightarrow 0} \frac{F(t+x) - F(t)}{R(t)} \cdot \frac{1}{x}$$

$$= \frac{1}{R(t)} \lim_{x \rightarrow 0} \frac{F(t+x) - F(t)}{x} = \frac{1}{R(t)} \cdot \frac{d}{dx} F(t) = \frac{f(t)}{R(t)}$$

(*) For exponential distribⁿ: $h(t) = \frac{f(t)}{R(t)} = \frac{\lambda e^{-\lambda t}}{e^{-\lambda t}} = \lambda$

(**) $h(t) \Delta t$: What is the prob of a component to ~~survive~~ ^{fail} in $(t, t+\Delta t]$, given that component has survived till t

$f(t) \Delta t$: What is the unconditional prob of a component to fail in $(t, t+\Delta t]$

Ques: $h(t) < / = / > f(t)$? [Hint: $h(t) = \lambda$
 $f(t) = \lambda e^{-\lambda t}$]

Relationship betⁿ reliability and instantaneous failure rate

$$h(x) = \frac{f(x)}{R(x)} = -\frac{R'(x)}{R(x)}$$

$$\int_{-\infty}^t h(x) dx = \int_{-\infty}^t -\frac{1}{R(x)} \cdot \frac{dR(x)}{dx} \cdot dx = -\int_{-\infty}^t \frac{dR(x)}{R(x)} = -[\ln R(x)]_{-\infty}^t$$

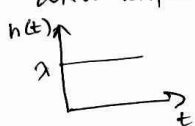
$$= -[\ln R(t) - \ln(R(-\infty))] = -[\ln R(t) - \ln 1] = -\ln R(t)$$

$$\ln R(t) = -\int_{-\infty}^t h(x) dx$$

$$\text{So, } R(t) = e^{-\int_{-\infty}^t h(x) dx}$$

Failure Rate

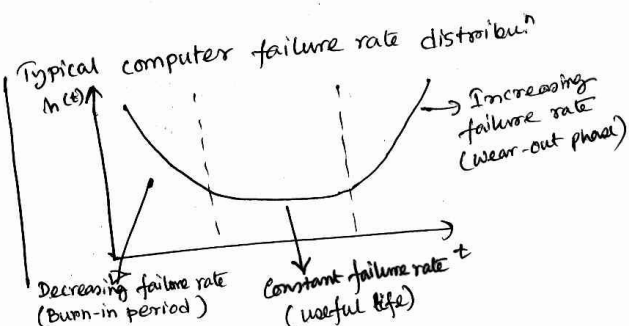
With exponential case:



$$f(t) = \lambda e^{-\lambda t}$$

$$R(t) = e^{-\lambda t}$$

$$h(t) = \frac{f(t)}{R(t)} = \lambda$$



② Weibull Distribution:

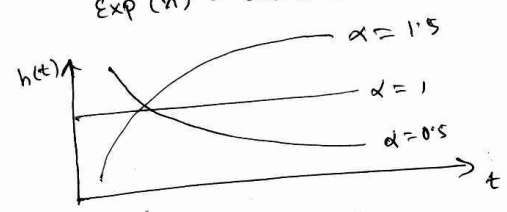
- The most widely used parametric family of failure distributions

$$\Rightarrow f(t) = \alpha t^{\alpha-1} e^{-\alpha t^\alpha}$$

$$F(t) = 1 - e^{-\alpha t^\alpha} \quad [\text{Here, the only difference is involvement of } \alpha]$$

$$h(t) = \frac{f(t)}{1-F(t)} = \frac{\alpha t^{\alpha-1} e^{-\alpha t^\alpha}}{e^{-\alpha t^\alpha}} = \alpha t^{\alpha-1}$$

$$\text{Exp}(\alpha) = \text{Weib}(\alpha, 1)$$



$\alpha \Rightarrow$ shape parameter
 $\alpha < 1$, Infant mortality
 $\alpha = 1$, constant hazard rate (exponential)
 $1 < \alpha < 4$, rising hazard (fatigue) } wear out
 $\alpha > 4$, rising hazard (rapid wearout)

- Proper choice of the shape parameter can make it IFR, DFR, or CFR

Another two Two more concepts

① Variance of X : $\sigma_x^2 = \int_0^\infty (x - E_x)^2 f(x) dx$
 $= \sum_k (x_k - E_x)^2 f(x_k)$

\rightarrow measure of spreading out of a set of numbers
 follow for a number lie from the mean

② Covariance of X and Y : $\psi_{X,Y} = E[(X - E_x)(Y - E_y)] = E[XY] - E_x E_y$

\rightarrow measure of how much two RVs vary together

Both \uparrow and \downarrow in a same way \rightarrow Cov is (+) ve

Both \uparrow and \downarrow " " reverse way \rightarrow " (-) ve

\Rightarrow sign shows the tendency of linear relationship betⁿ the variables

\rightarrow magnitude not easy to interpret;

normalized val of cov \Rightarrow gives strength of linear relⁿship

$$\frac{\int (x-y)(x-y) dx}{\sqrt{\int (x-y)^2 dx} \sqrt{\int (x-y)^2 dy}}$$

Mean Time to Failure (MTTF)

$$E(T) = \text{MTTF} = \int_0^\infty R(t) dt = \int_0^\infty t f(t) dt, \text{ as } E(x) = \int_0^\infty x f(x) dx$$

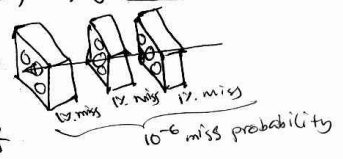
Example: Exponential \rightarrow $\text{MTTF} = 1/\alpha$

Weibull \rightarrow $\text{MTTF} = (1/\alpha) \Gamma(1 + 1/\alpha)$

Derivaⁿ
 $\text{MTTF} = \int_0^\infty t f(t) dt$
 $= \int_0^\infty t \frac{d}{dt} F(t) dt = - \int_0^\infty t \frac{d}{dt} R(t) dt$
 $= \left[-t R(t) + \int_0^\infty R(t) dt \right]_0^\infty = \int_0^\infty R(t) dt$
 as $R(t) \rightarrow 0$ if $t \rightarrow \infty$

Why are we ~~doing~~ going so deep? Why not simply use layers of safeguards?

\rightarrow With multiple layers, a system fails only if warning symptoms and compensating actions are missed at every layer, which is quite unlikely.



* * * Multiple layers increase the reliability significantly only if the "holes" are fairly randomly and uniformly distributed, so that the probability of their being aligned is negligible.

Concepts related to failures & repairs

- * Mean Time To Failure (MTTF): Expected time till the first failure
- * Mean Time To Repair (MTTR): Expected time required to repair a failed module
- * Mean Time Between Failure (MTBF): " " bet. two consecutive failures
- * Rel. ship: $MTBF = MTTF + MTTR$, where, $MTTF = \frac{1}{\lambda}$ for exp

Now, λ \rightarrow failure rate, μ \rightarrow repair rate

$$MTTR = \frac{1}{\mu}$$

$$\text{availability} = \frac{MTTF}{MTTF + MTTR} = \frac{\frac{1}{\lambda}}{\frac{1}{\lambda} + \frac{1}{\mu}} = \frac{1}{1 + \frac{\lambda}{\mu}} \quad \left[\text{if repair happens} \right] = \frac{\text{\# of repairs}}{\text{time period for all repairs}}$$

② (availability = reliability [if no repair happens])

In case of a system either non-repairable, i.e., $MTTR = 0$, or negligible repair time, i.e., $MTTR \ll MTTF$,

$$MTBF \approx MTTF = \int_0^{\infty} R(t) dt$$

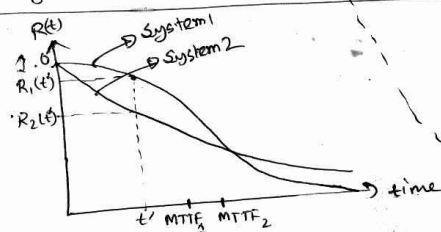
Relationships between pdf, cdf, reliability, and hazard funcⁿ

Expression in terms of	$f(t)$	$F(t)$	$R(t)$	$z(t)$
$f(t) =$	—	$\frac{dF(t)}{dt}$	$-\frac{dR(t)}{dt}$	$z(t) e^{-\int_0^t z(t) dt}$
$F(t) =$	$\int_0^t f(t) dt$	—	$1 - R(t)$	$1 - e^{-\int_0^t z(t) dt}$
$R(t) =$	$\int_t^{\infty} f(t) dt$	$1 - F(t)$	—	$e^{-\int_0^t z(t) dt}$
$z(t) =$	$\frac{f(t)}{\int_t^{\infty} f(t) dt}$	$\frac{dF(t)/dt}{1 - F(t)}$	$-\frac{d}{dt} \ln R(t)$	—

Comparing Reliabilities

- ① Reliability difference: $R_2 - R_1$ ② Reliability gain: R_2/R_1 ③ Reliability improvement factor: $RIF_{2,1} = \frac{1 - R_1(t_m)}{1 - R_2(t_m)}$
- Ex: $R_1(t_m) = 0.9$; $R_2(t_m) = 0.99$; $RIF_{2,1} = \frac{1 - 0.9}{1 - 0.99} = 10$
- ④ Rel. impv. index: $RII = \frac{\log R_1(t_m)}{\log R_2(t_m)}$ ⑤ Mission time extension: $MTE_{2,1}(t_m) = T_2(R_2) - T_1(R_2)$ ⑥ Mission time impv. factor: $MTIF_{2,1}(t_m) = T_2(R_2)/T_1(R_2)$

Does comparing reliabilities indicate in the same way of comparing MTTFs?



$MTTF_2 > MTTF_1$
However, at $t = t'$, $R_1(t') > R_2(t')$
So, reliability can be much more imp. than MTTF if mission time is known a priori
[Ex: if mission time $\leq t'$, then System 1 is the better choice even though it has a lower MTTF]

Analogy of Amdehl's law for Reliability

Amdehl's law: If a unit-time computer, a fracⁿ f does not change and the remaining fraction $1-f$ is speeded up to run p times faster, then the overall speedup will be $S = \frac{1}{f + \frac{(1-f)}{p}}$

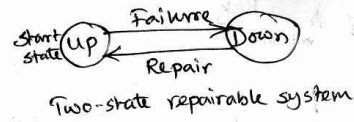
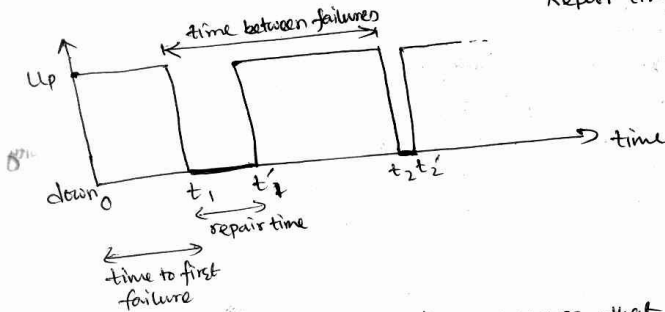
Reliability: Let a system has two parts having failure rates of ϕ and $\lambda - \phi$. If the second part is improved by a factor p to $\frac{\lambda - \phi}{p}$. So, $R_{org} = e^{-\lambda t}$, $R_{imp} = e^{-(\phi + \frac{\lambda - \phi}{p})t}$

$$RII = \frac{\log R_{org}}{\log R_{imp}} = \frac{\lambda}{\phi + (\lambda - \phi)/p} = \frac{1}{\frac{\phi}{\lambda} + (1 - \frac{\phi}{\lambda})/p} = \frac{1}{f + (1-f)/p} \quad \text{if } f = \frac{\phi}{\lambda}$$

[So, it is not part of a system, rather part of the failure rate of a part]

Some other concepts

* Maintainability (serviceability) : Ability to maintain, which is related to repair time
Repair time ↓ : Good maintainability



* Performability (P) : A composite measure that covers both performance and reliability

Example :

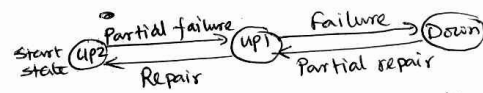
→ Worth of 'Up2' is twice that of 'Up1'

P_{up_i} = prob of being in state Up_i

$$\text{So, } P = 2 * P_{up_2} + P_{up_1}$$

↑
impact of
performance

↑
impact of reliability



Three-state dependable system

$$P_{up_2} = 0.92, P_{up_1} = 0.06, \text{ and } P_{down} = 0.02$$

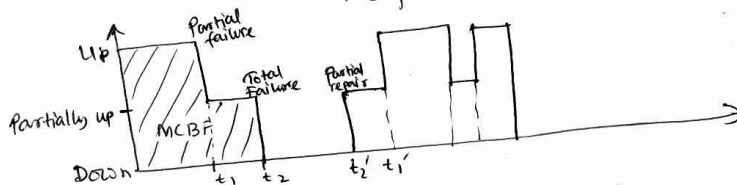
= 1.90 ← System performance is equivalent to that of having 1.9 components on avg. (even though we are physically using 2 components)

⇒ Performability improvement factor of this system (similar to RIF) in comparison to

a fail-hard system, which goes down when the system leaves up_2 state.

$$PIF = (2 - 2 \times 0.92) / (2 - 1.9) = 1.6$$

↑
Performability of
the fail-hard system



MCBF
Mean Cycles Betⁿ
Failures

* Integrity and Safety : (Similar concepts)

→ Integrity is inward-looking : Capacity to protect system resources (e.g., data)

→ Safety is outward-looking : Consequences of incorrect actions to users

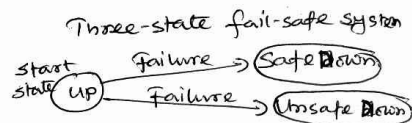
⇒ Safety is different from reliability : A fail-safe system may not be very reliable in the traditional sense

Basic safety assessment

→ Risk : Prob of being in "Unsafe down" state

⇒ Simple analysis : Merge 'Up' and 'Safe Down' states

⇒ More detailed : Treat each state separately



[There can be multiple unsafe states]

⇒ Quantifying safety:

$$\text{Risk} = \text{Frequency} \times \text{Magnitude}$$

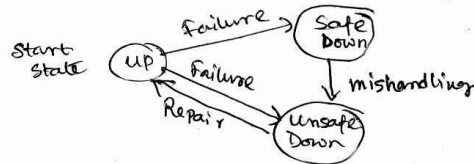
(Consequence/Unit time) (Events/Unit time) (Consequence/Unit time)
Event

$$\text{Risk} = \text{Probability} \times \text{Severity}$$

→ Magnitude or severity is measured in suitable unit (ex: \$)

⇒ If there are multiple unsafe outcomes, the probability of each is multiplied by its severity (cost) and the results added up.

⇒ A safe failure can become unsafe or an unsafe failure can turn into a more severe safety problem due to mishandling or human error [can be modeled by adding appropriate transition]



* Privacy and Security: Human-related

→ Privacy: Confidentiality and authorized access of data

Security: Proper modification of data

⇒ Security is distinct from reliability and safety: A secure system (automatically locks up when a breach is suspected) may not be very reliable or safe

⇒ Quantifying security:

$$\text{Risk} = \text{Frequency} \times \text{Magnitude}$$

$$\text{Risk} = \text{Probability} \times \text{Severity}$$

⇒ Security breaches are not generally suited for probabilistic treatment as such breaches are often not accidental.

Markov modeling:

→ Markov Model: Analyzes systems having "Markovian Property", which indicates "memoryless" characteristic. The char can be described as

- Future state of a system depends only on its current state.

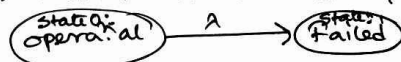
- All transitions from one state to another occur at constant rates.

→ Significance: A large class of real-world devices (such as electronic components) exhibit constant failure rates, and therefore be effectively represented and analyzed using Markov models.

(⇒ Sometimes Markov modeling also covers variable failure rates)

⇒ Modeling approach:

- Consists a set of possible states, possible transition paths, and rate parameters of those transitions. Example:



- $P_j(t)$ denotes the probability of the system of being in state j at time t . Example: $P_0(0) = 1$, $P_1(0) = 0$

Now, $\frac{dP_0}{dt} = - (P_0) (\lambda dt)$
 incremental change in the prob of being at state 0 the prob of being at state 0 at the beginning of interval λdt The probability of transition during the interval dt

So, $\frac{dP_0}{dt} = -\lambda P_0$

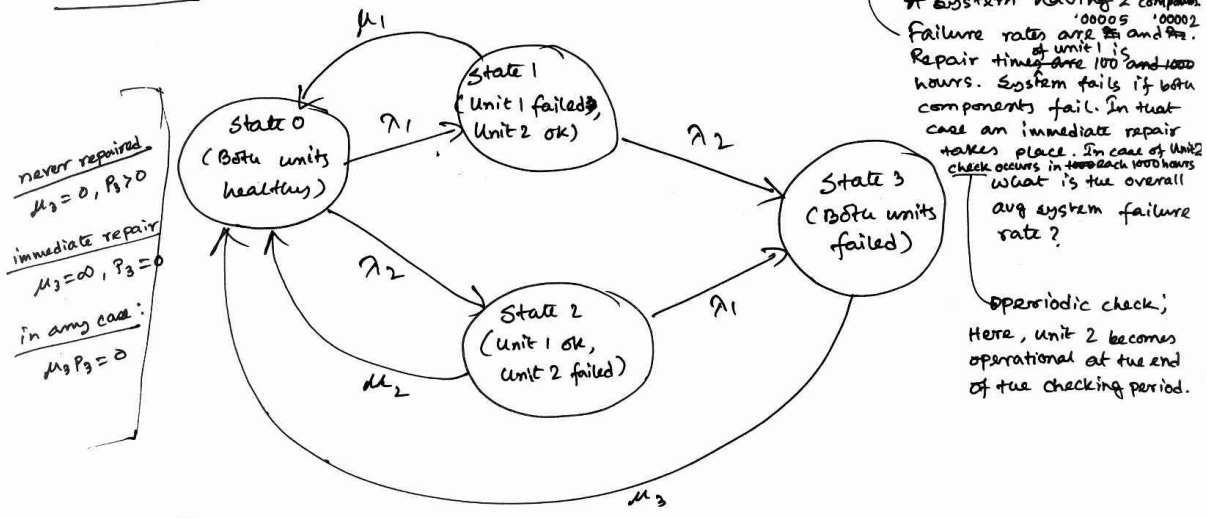
Now, $P_0 + P_1 = 1$ gives $\frac{dP_0}{dt} + \frac{dP_1}{dt} = 0$

So, $\frac{dP_1}{dt} = \lambda P_0$

$\ln P_0 = -\lambda t$; So, $P_0(t) = e^{-\lambda t}$

Therefore, $P_1(t) = 1 - e^{-\lambda t}$

Example:



$\lambda_1 = 0.0005$, $\lambda_2 = 0.0002$, $\mu_1 = 1/100$, $\mu_2 = 1/1000$
 $\frac{1}{\lambda_2} = P(1+2+\dots+\infty) = \frac{1+2+\dots}{2} \cdot \frac{1}{\lambda_2}$
 So, $\mu_2 = 1/\text{time} \approx 2/1000$

$\mu_3 = \infty$, but $P_3 = 0$

Now,

$(\lambda_1 + \lambda_2) P_0 = \mu_1 P_1 + \mu_2 P_2 + \mu_3 P_3$ — ①
 $\lambda_1 P_0 = (\lambda_2 + \mu_1) P_1$ — ②
 $\lambda_2 P_0 = (\lambda_1 + \mu_2) P_2$ — ③
 $\lambda_2 P_1 + \lambda_1 P_2 = \mu_3 P_3$ — ④

from ①, ④ $\Rightarrow (\lambda_1 + \lambda_2) P_0 = (\mu_1 + \lambda_2) P_1 + (\lambda_1 + \mu_2) P_2$

③ $\Rightarrow P_1 = \frac{\lambda_1 P_0}{\lambda_2 + \mu_1}$; ② $\Rightarrow P_2 = \frac{\lambda_2 P_0}{\lambda_1 + \mu_2}$

as unit 2 has periodical checking, [assuming failure occurring in a uniform manner, i.e., same prob of failure occurring at the beginning & end of an interval]

Now, $P_3 = 0$

So, $P_0 + P_1 + P_2 = 1$

So, $P_0 + \frac{\lambda_1 P_0}{\lambda_2 + \mu_1} + \frac{\lambda_2 P_0}{\lambda_1 + \mu_2} = 1$

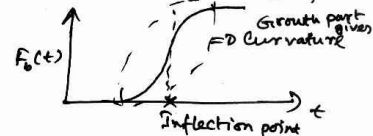
So, $P_0 = \frac{1}{1 + \frac{\lambda_1}{\lambda_2 + \mu_1} + \frac{\lambda_2}{\lambda_1 + \mu_2}}$

Now, overall avg system failure rate will be

$$\lambda_{sys} = \lambda_2 P_1 + \lambda_1 P_2 = \frac{\lambda_2 \frac{\lambda_1}{\lambda_2 + \mu_1} + \lambda_1 \frac{\lambda_2}{\lambda_1 + \mu_2}}{1 + \frac{\lambda_1}{\lambda_2 + \mu_1} + \frac{\lambda_2}{\lambda_1 + \mu_2}}$$

= \$0.00000579\$ per hour

Example: A system consists of a device and a battery. pdf for the failure of the device is given by $f(t) = \lambda \alpha t^{\alpha-1} e^{-\lambda t^\alpha}$. Reliability of the battery ~~follows~~ decaying follows a sigmoid curve having curvature a and inflection point b , i.e., $F_b(t) = \frac{e^{a(t-b)}}{1 + e^{a(t-b)}}$. What is the reliability of the system.



Soln:

$X_d \sim \text{Weibull}(\lambda, \alpha)$

$X_b \sim \text{Sigmoid}(a, b)$

Now $X_s \sim \text{Min}(X_d, X_b)$

$$\begin{aligned} R_s(t) &= \Pr\{\min(X_d, X_b) > t\} = \Pr\{X_d > t \text{ and } X_b > t\} \\ &= \Pr\{X_d > t\} \times \Pr\{X_b > t\} = R_d(t) \times R_b(t) \\ &= e^{-\lambda t^\alpha} \cdot \left(1 - \frac{e^{a(t-b)}}{1 + e^{a(t-b)}}\right) \\ &= \frac{1}{e^{\lambda t^\alpha} + e^{a(t-b)} + \lambda t^\alpha} \end{aligned}$$

Q: You are given with two independent computing systems. Let X_1 and X_2 denote time lag between arrivals of two successive jobs in the two systems respectively. Here, the job arrivals follow two different Poisson distributions having rates of λ_1 and λ_2 respectively. Determine the probability of X_1 being less than X_2 .

Ans: (Slide 14 in V20.pdf)

$P\{X_1 < X_2\}$

[$X_1, X_2 \rightarrow$ Exponential RVs as corresponding arrivals follow Poisson distribution]

$$\begin{aligned} &= \int_0^\infty P\{X_1 < X_2 | X_1 = x\} f(x) dx = \int_0^\infty P\{X_1 < X_2 | X_1 = x\} \lambda_1 e^{-\lambda_1 x} dx \\ &= \int_0^\infty P\{x < X_2\} \lambda_1 e^{-\lambda_1 x} dx = \int_0^\infty e^{-\lambda_2 x} \lambda_1 e^{-\lambda_1 x} dx = \int_0^\infty \lambda_1 e^{-(\lambda_1 + \lambda_2)x} dx = \frac{\lambda_1}{\lambda_1 + \lambda_2} \end{aligned}$$